

Title (en)

METHOD AND DEVICE FOR TESTING THE QUALITY OF PRINTED CIRCUITS

Title (de)

VERFAHREN UND VORRICHTUNG ZUR QUALITÄTSPRÜFUNG VON LEITERPLATTEN

Title (fr)

PROCEDE ET DISPOSITIF DE CONTROLE DE QUALITE SUR DES CARTES DE CIRCUITS IMPRIMES

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Abstract (en)

[origin: WO02067002A1] The invention relates to a method and to a device for testing electronic circuits or the parts thereof on printed circuits. The inventive method comprises the following steps: (a) detecting the radiation that is emitted by the surface of the printed circuit, (b) converting the detected radiation to data that represent a surface structure and/or depth structure of the printed circuit, (c) comparing the data of the surface structure and/or the depth structure with stored data of a desired state of the surface structure and/or depth structure, and (d) determining any deviations between the data of the detected surface structure and/or depth structure and the data of the desired state of the surface structure and/or depth structure.

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